Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/785,445	WANG ET AL.
Examiner	Art Unit
Matthew D. Matzek	1771

	SEAR	CHED	
Class	Subclass	Date	Examiner
445	82,88,94	11/20/05	мм
977	016.1	11/20/05	мл
428	400	11/30/05	мм
search:			
442	221	6/19/06	мм
	268		
	315 319		
	370 381		
	394		
428	174~		
	180~	1	J

	INTERFERENCE SEARCHED					
Subclass	Date	Examine				
	Subclass	Subclass Date				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	11/05	мл		
INVENTOR ASSIGNEE	11/30/15	אע		
192	12/1/05	мм		
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